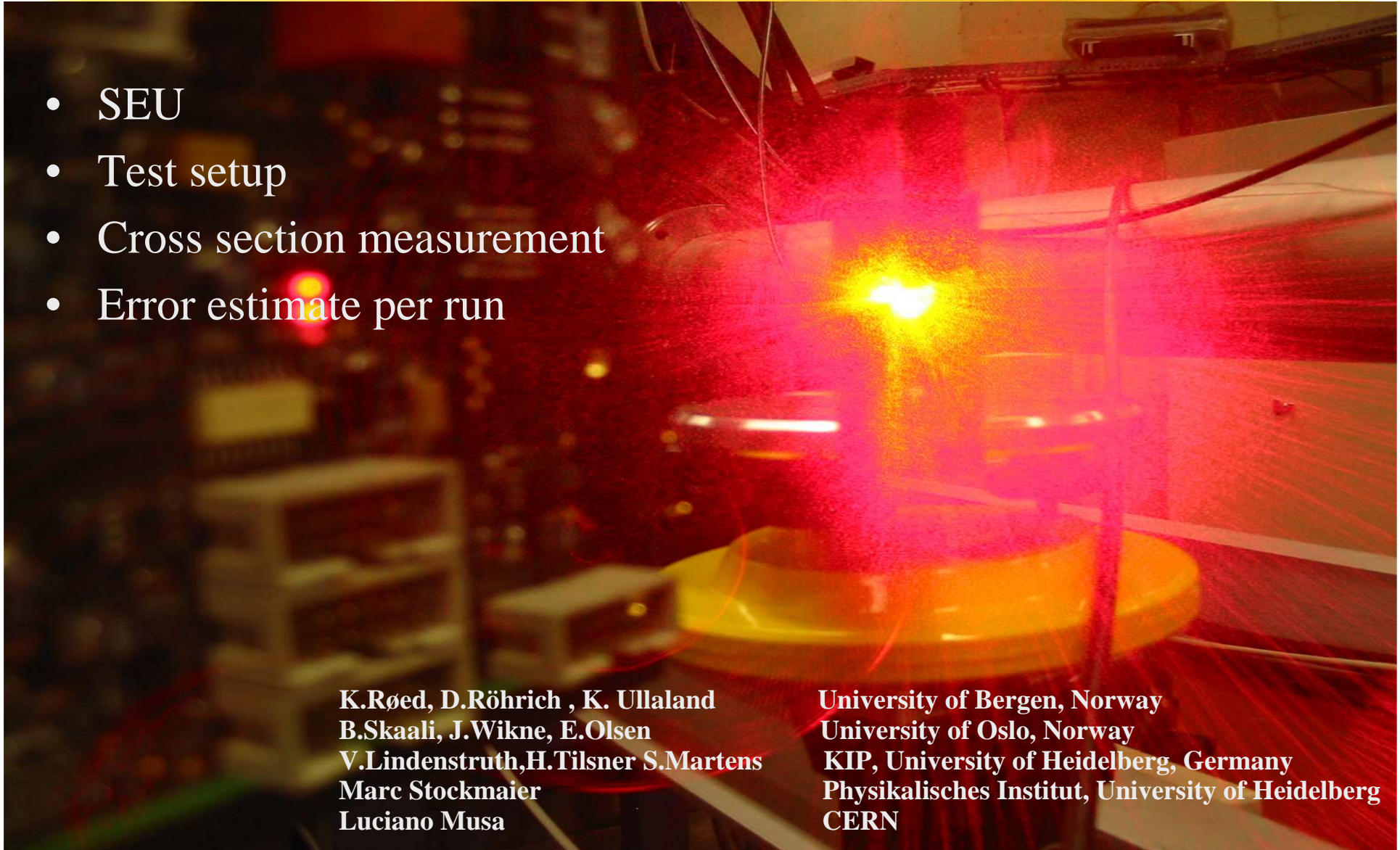


Irradiation results

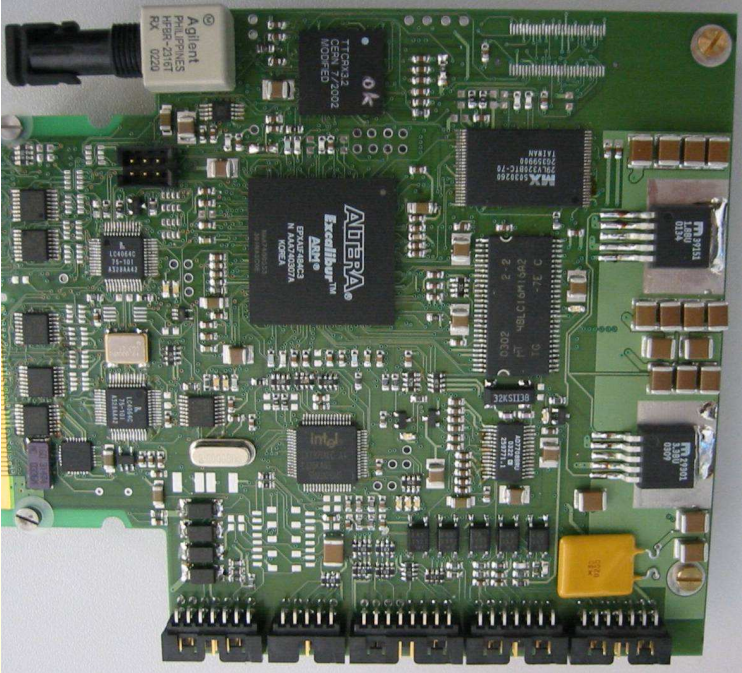
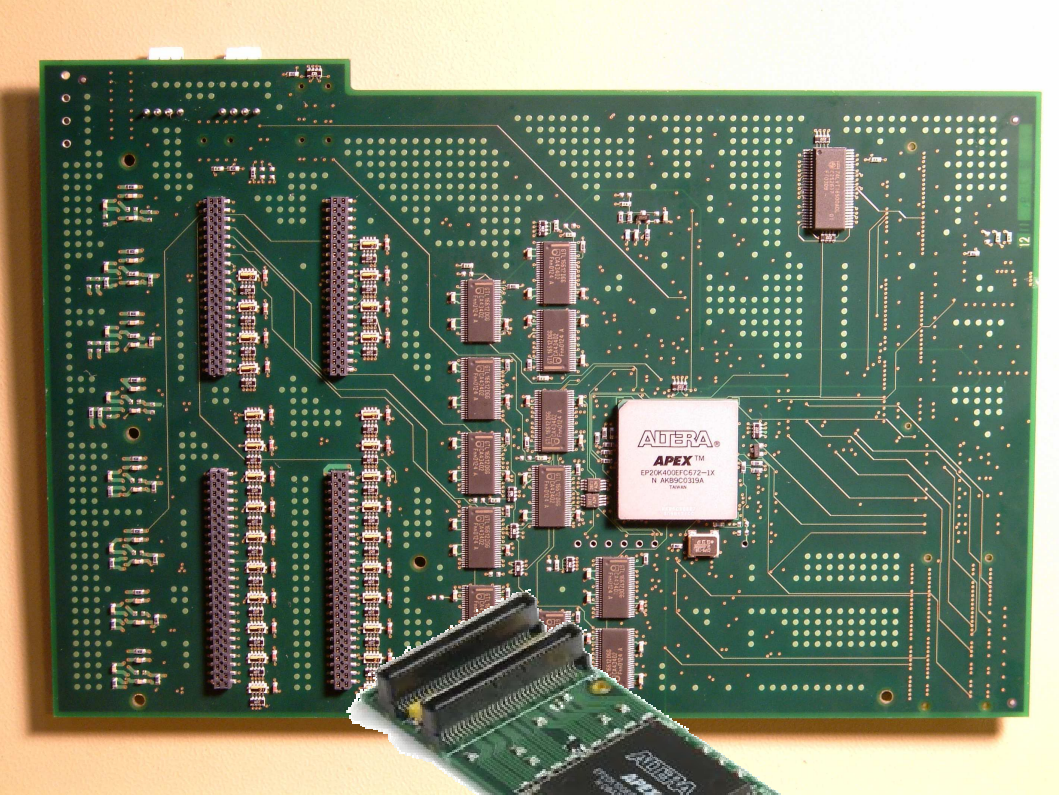
- SEU
- Test setup
- Cross section measurement
- Error estimate per run

**K.Røed, D.Röhrich , K. Ullaland
B.Skaali, J.Wikne, E.Olsen
V.Lindenstruth,H.Tilsner S.Martens
Marc Stockmaier
Luciano Musa**

**University of Bergen, Norway
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Physikalisches Institut, University of Heidelberg
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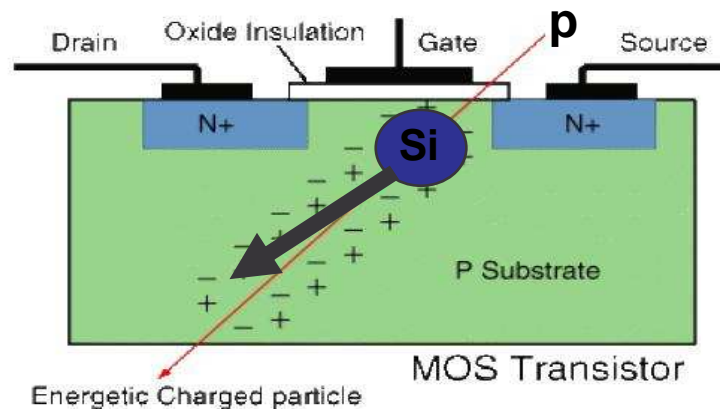


FPGAs on RCU mother/mezzanine boards



Single Event Upset (SEU)

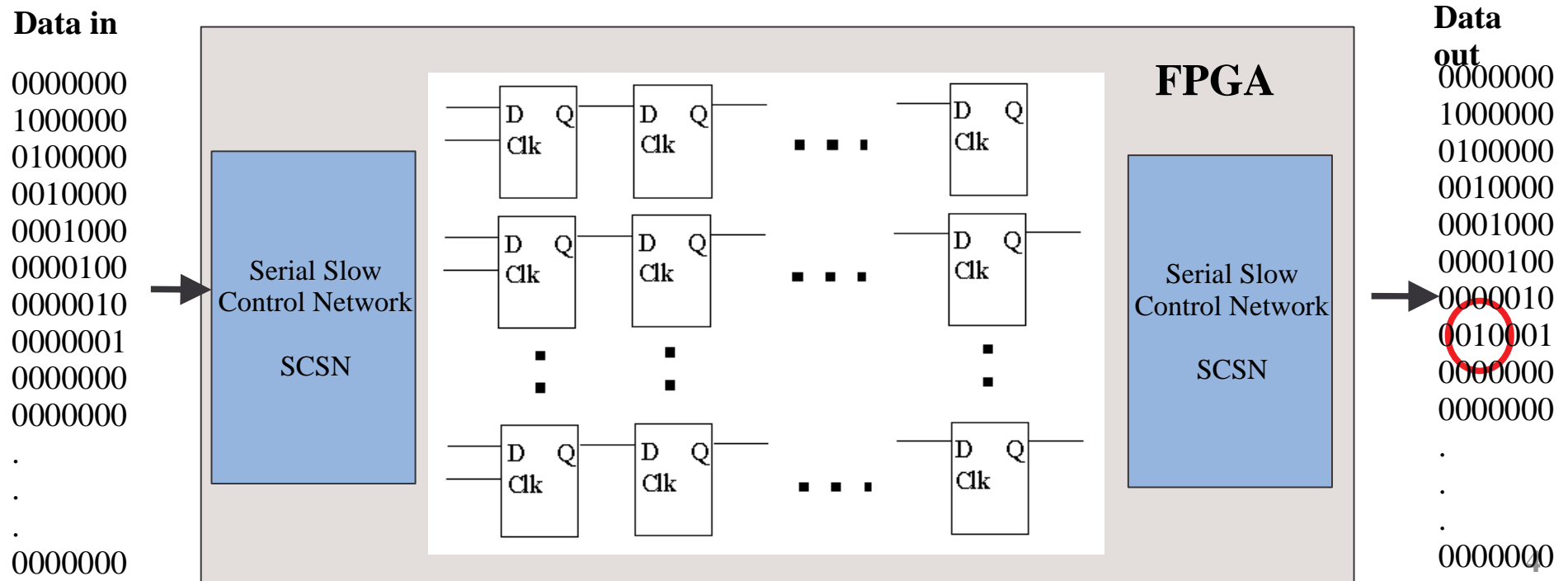
- High-energetic hadrons induce nuclear reactions in the silicon ($E > 20$ MeV - protons, neutrons, pions, kaons)
- Intermediate energy neutrons (2 MeV $< E < 20$ MeV) contribute little (10%) to SEUs
- (Almost) no effect due to thermal neutrons
- Heavy recoil ions from reactions ionize the material
- Charge deposition leads to a change in state of a transistor (SEU)
- Soft error – can be corrected (rewriting or reprogramming)



- $\text{Si}(p,2p)\text{Al}$
- $\text{Si}(p,p\alpha)\text{Mg}$
- $\text{Si}(n,p)\text{Al}$
- $\text{Si}(n,\alpha)\text{Mg}$

Upset detection in ALTERA FPGAs

- Two types of concern
 - Upsets in configuration SRAM cells
 - Single bitflips in register elements
- The APEX20K400E offers no direct readout of configuration SRAM
 - Indirectly detection of configuration upset through the VHDL design
 - Error observed reflects a change in logic due to a configuration upset, and not the configuration upset itself
 - A fixed pattern is shifted through and compared for setups when read out



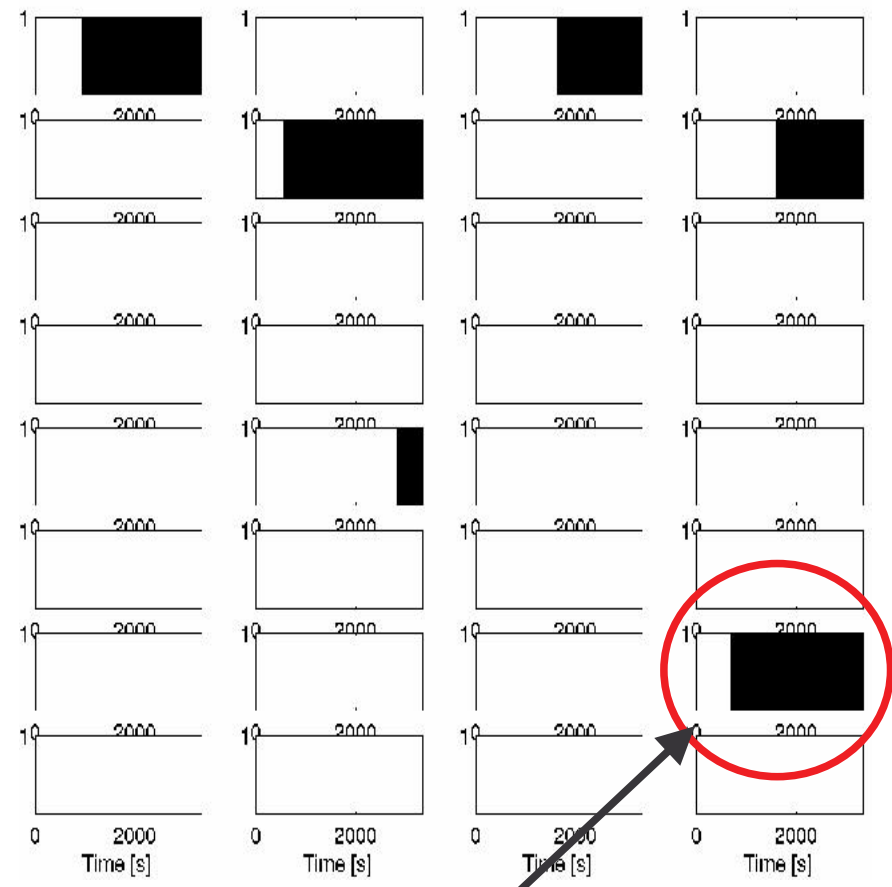
Example of analyzing data

FIFO in internal RAM



Single upset

Shiftregister in logic elements



Configuration upset

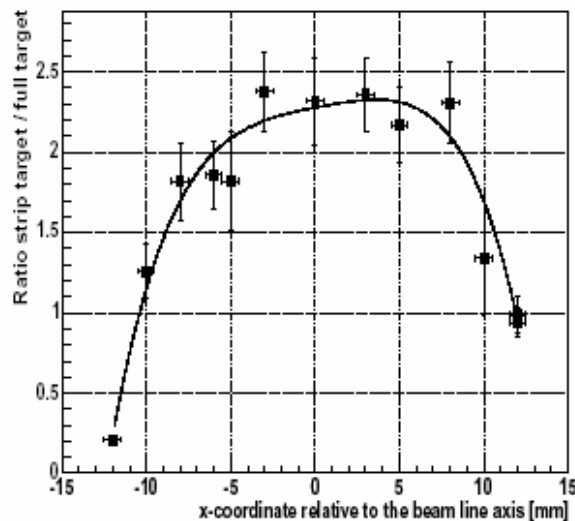
Test setup (1)

- **Oslo Cyclotron**

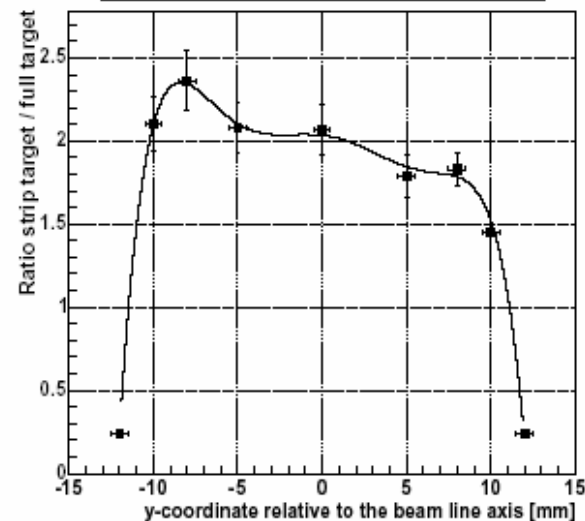
- 25 and 28 MeV external proton beam
- flux $\sim 10^7 - 10^8$ protons/s cm^2
- Flux measurements: Uranium fission target + TFBC
- Intensity monitor: faraday cup
- Beam profile: spot 1.5cm x 1.5cm



OCL-March 2004, Beamprofile at 160 cm from beam exit point



OCL-March 2004, Beamprofile at 160 cm from beam exit point



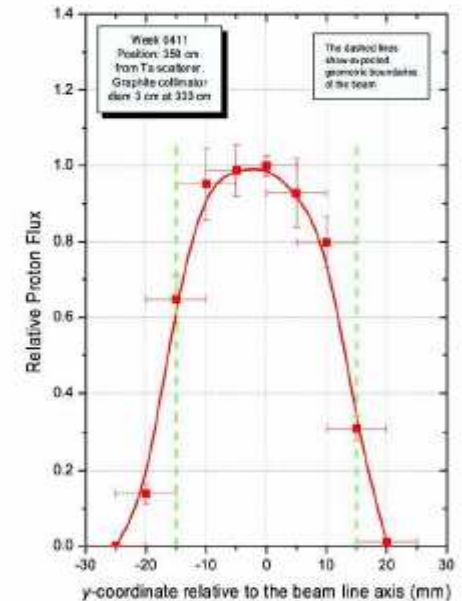
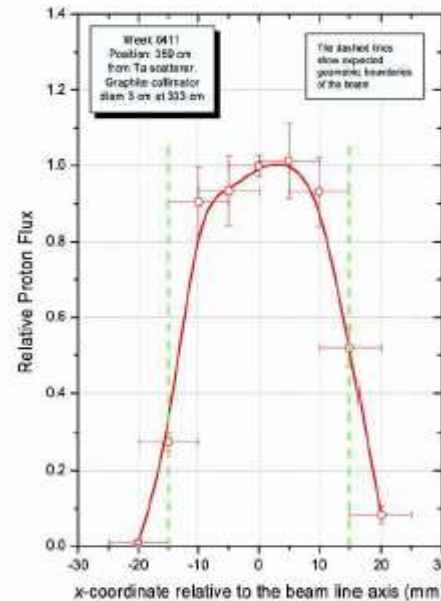
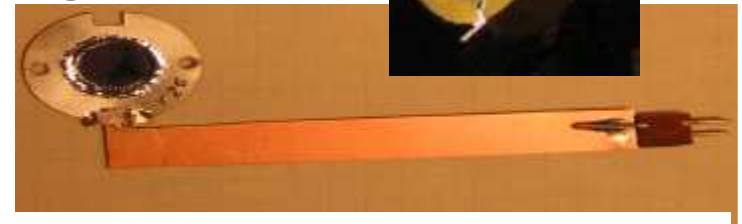
Test setup (2)

- TSL (Uppsala)

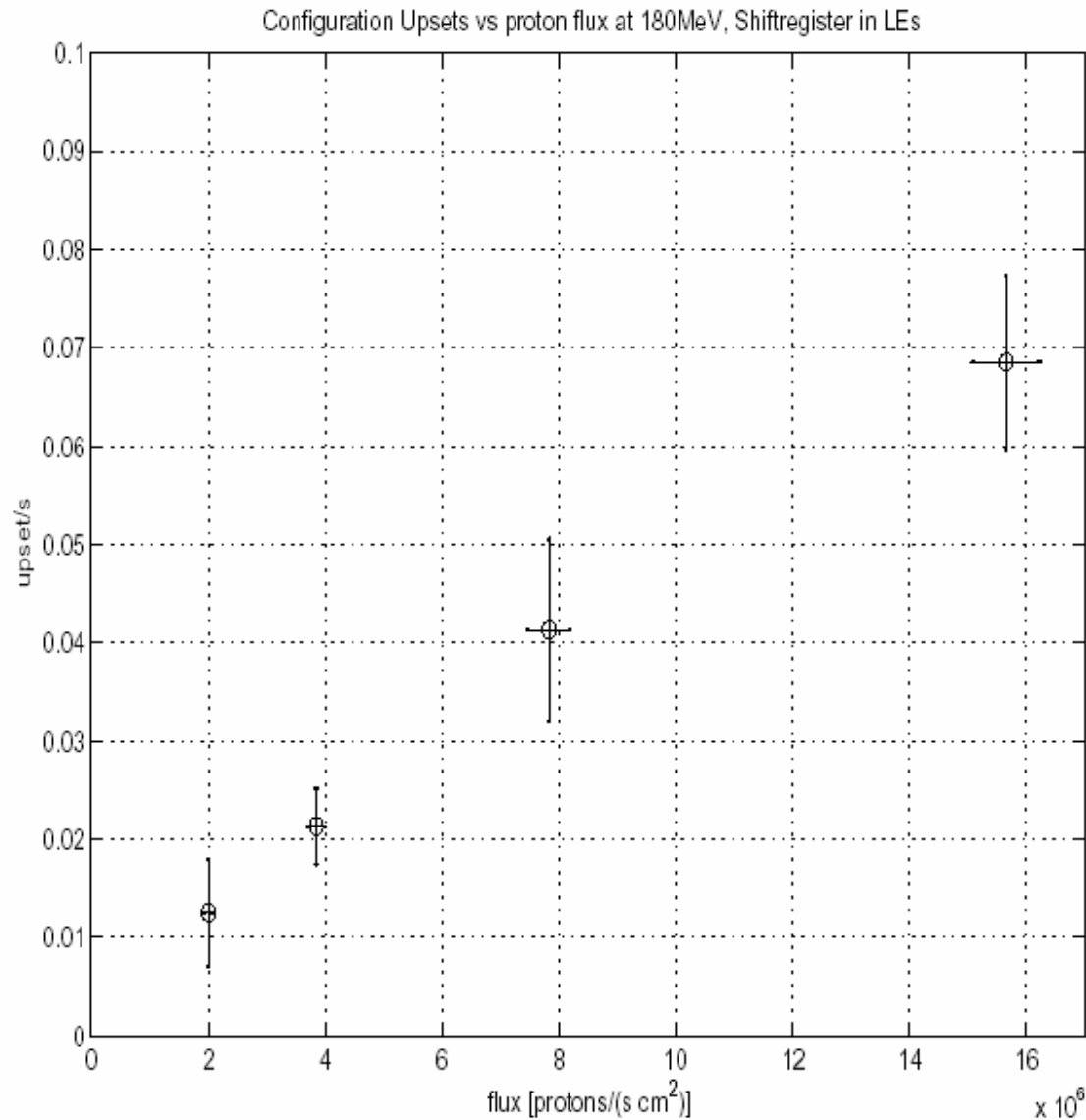
- 38 and 180 MeV external proton beam
- flux $\sim 10^7 - 10^8$ protons/s cm^2
- Flux measurements: Uranium fission target + TFBC

- Intensity monitor
 - » scattered protons -> scintillator

- Beam profile:
 - » spot \varnothing 3cm



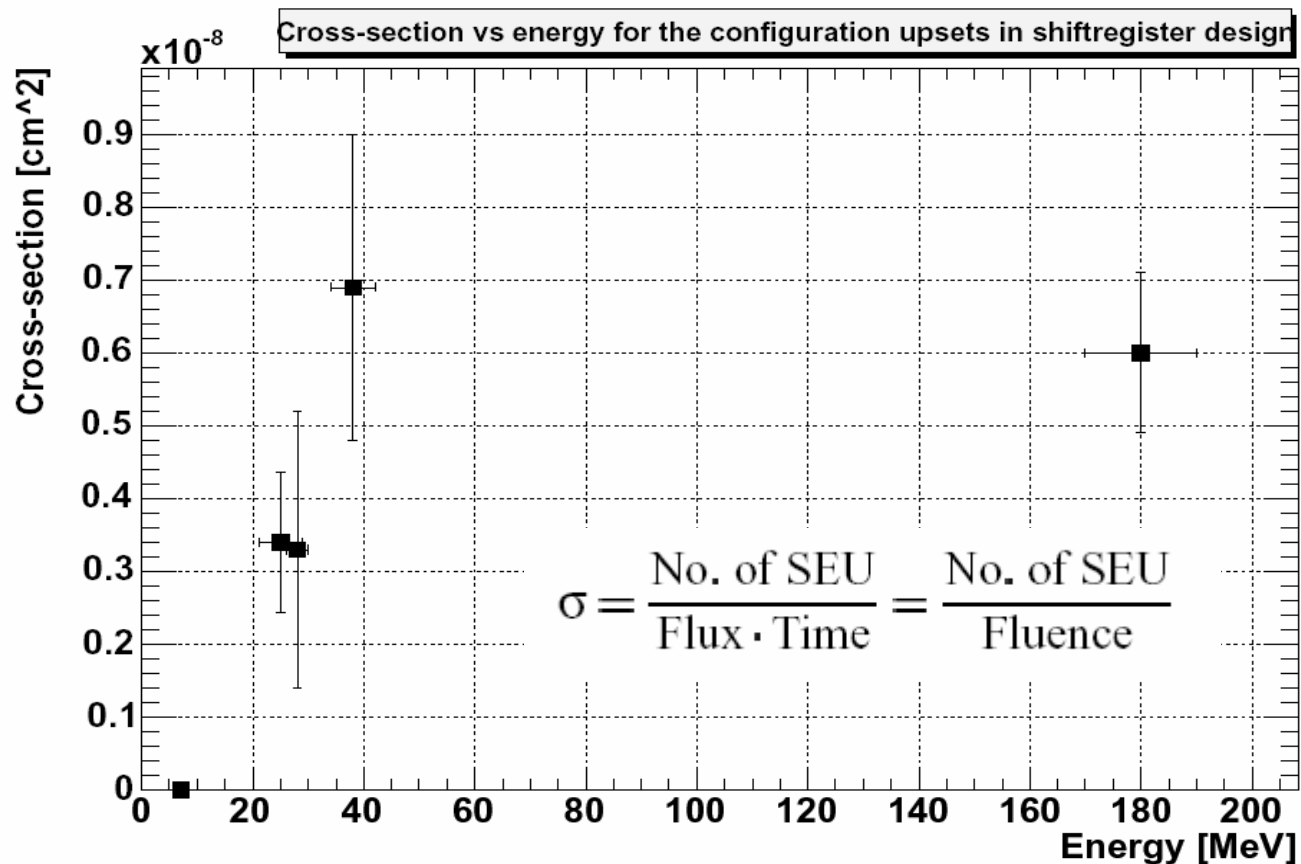
Results (1)



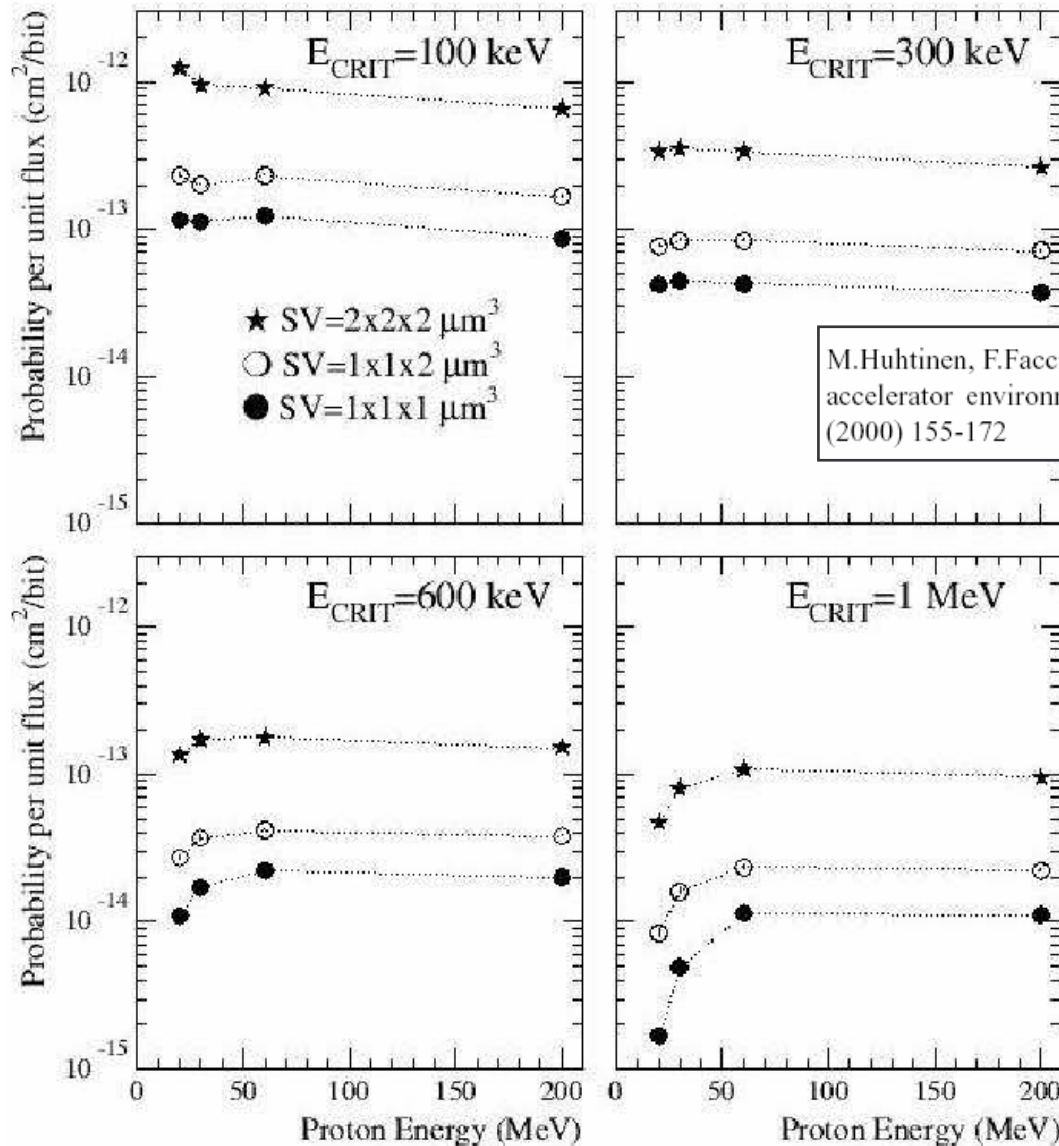
- **APEX20k400**
 - configuration-SRAM upset rate

Results (2)

- **APEX20k400**
 - Energy dependence of cross section
 - **CS = $6.0 \times 10^{-9} \pm 1.1 \times 10^{-9} \text{ cm}^2$ (E >30 MeV)**

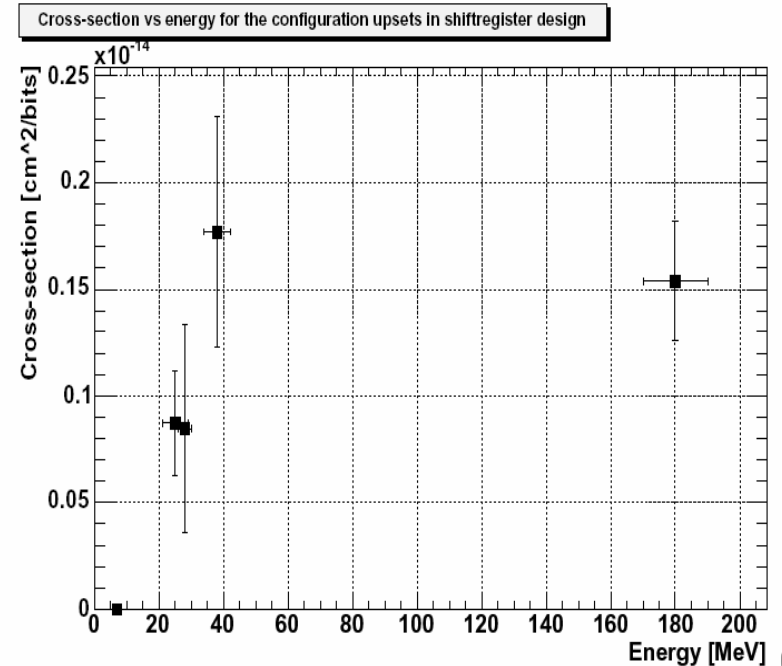


Results (3)



- **Energy dependence of cross section - comparison to simulations**

M.Huhtinen, F.Faccio, Computational method to estimate Single Event Upset rates in and accelerator environment, Nuclear Instruments & Methods in Physics Research, A 450 (2000) 155-172



Results (4)

- **APEX EP20K60E - SIU**

See Trigger/DAQ/HLT/Controls-TDR, p. 142 (DAQ section)

Proton energy (MeV)	SEU cross section (cm²)	CL cross section (cm²)
180	1.56 x 10⁻⁹	
100	1.70 x 10⁻⁹	1.50 x 10⁻⁹

Results (5)

- **ALTERA EPXA1F484C1 - ARM**

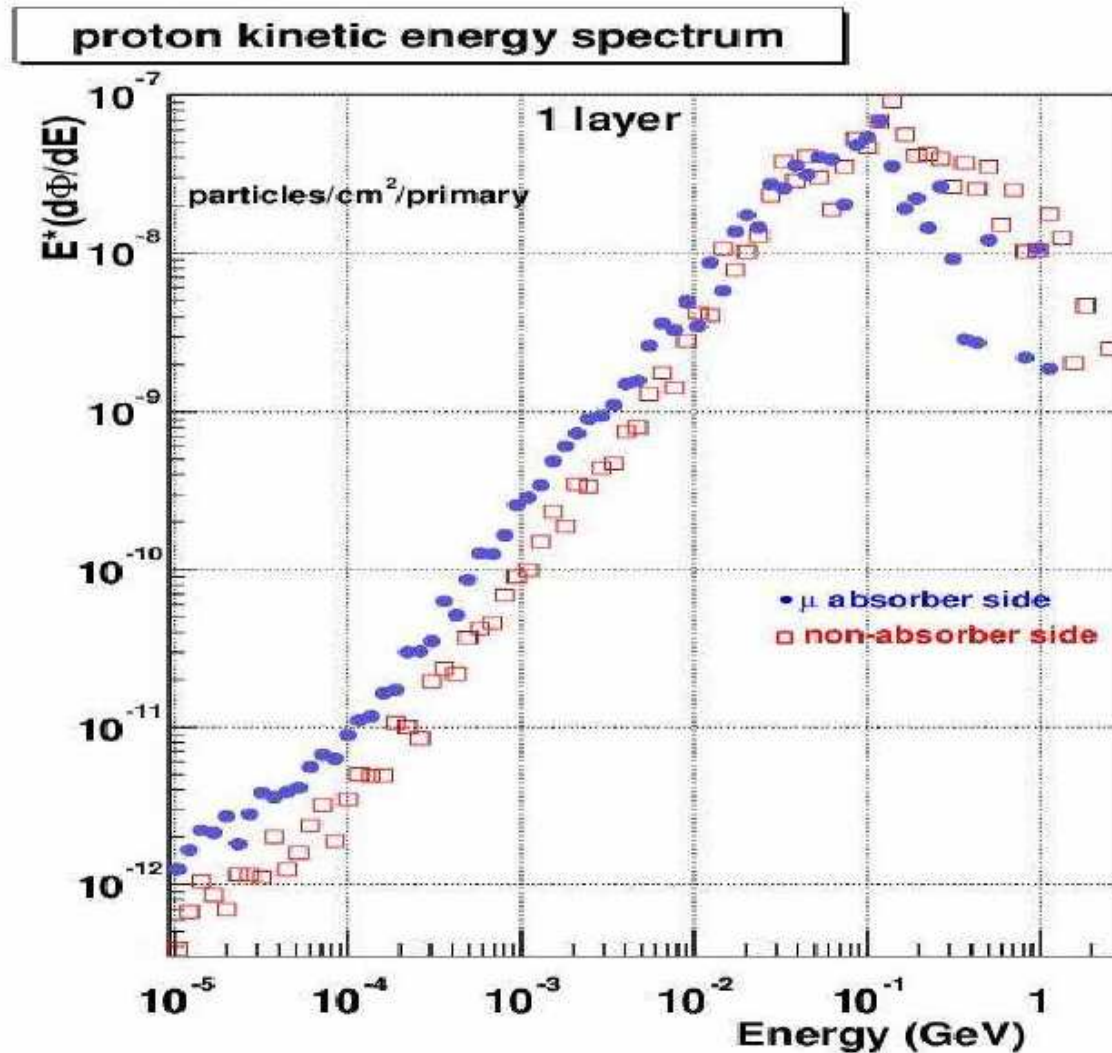
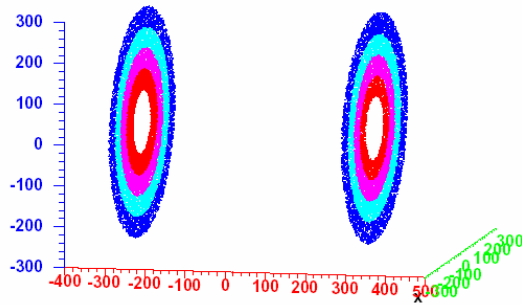
See S. Martens, Diploma thesis, KIP (2003)

Flux @ 28 MeV (protons/s cm²)	Mean time between failures (s)	cross section (cm²)
3 x 10⁶	360	1 x 10⁻⁹
7 x 10⁶	140	1 x 10⁻⁹
2 x 10⁷	50	1 x 10⁻⁹

Cross section results - summary

	Cross section [cm ²]
RCU FPGA	$6.0 \times 10^{-9} \pm 1.1 \times 10^{-9}$
SIU	1.6×10^{-9}
DCS	2×10^{-9} (scaled to $E > 30$ MeV)

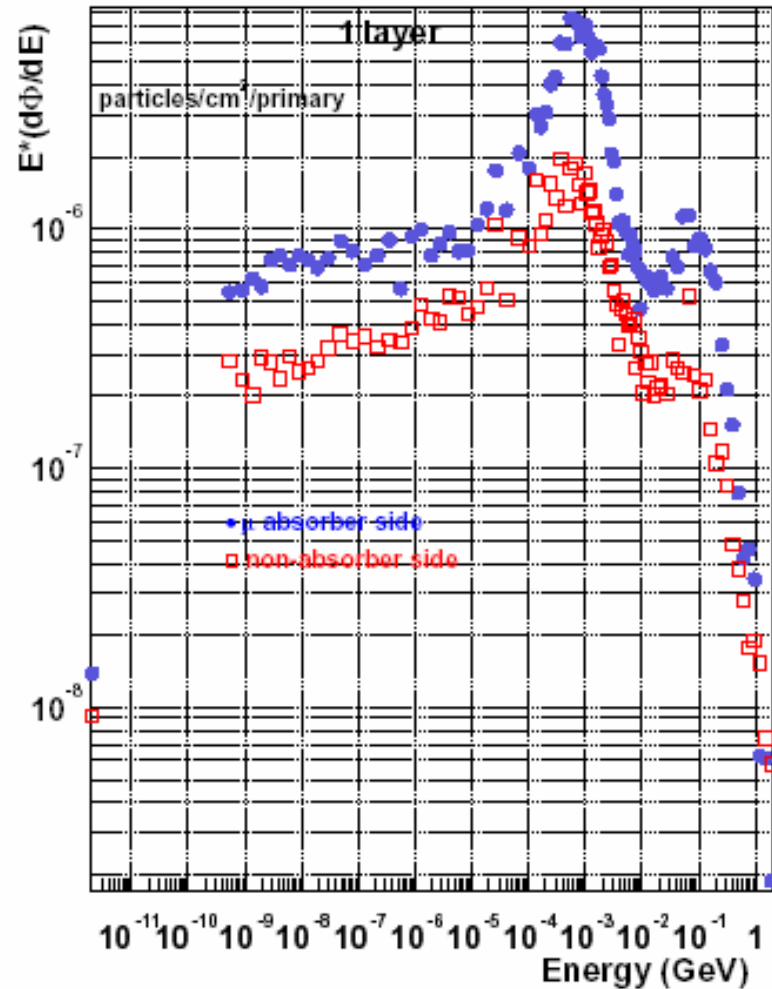
Radiation levels – simulation (1)



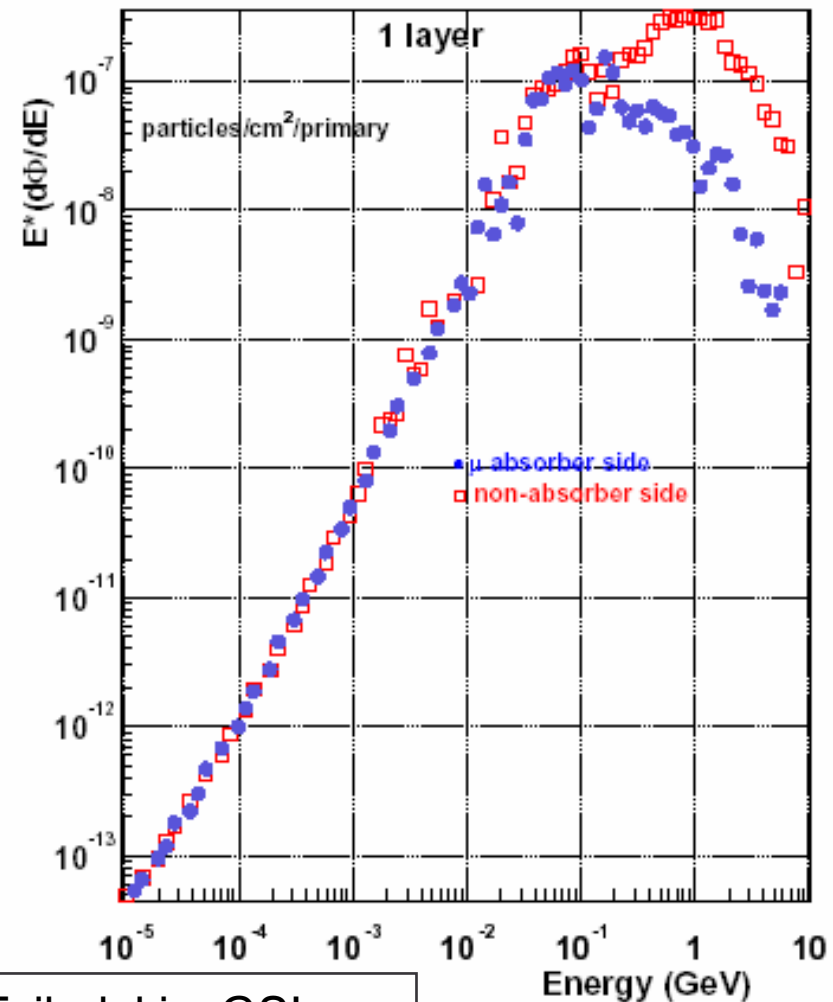
Georgios Tsiledakis, GSI

Radiation levels – simulation (2)

neutron kinetic energy spectrum



pion kinetic energy spectrum



Georgios Tsiledakis, GSI

Radiation levels – simulation (3)

Table 3.3: Particle fluxes (particles/cm²/s) for minimum bias Pb-Pb running (**absorber side**)[2]

Layers	1	2	3	4
Neutron Flux [cm ⁻² s ⁻¹]	4377.6±1.6%	3289.6±0.3%	2726.4±0.9%	2368±0.5%
Neutron Flux [cm ⁻² s ⁻¹] with E _{kin} > 10 MeV	334.1	204.8	134.4	959
Proton Flux [cm ⁻² s ⁻¹]	13.2±26.7%	7.7±6.9%	5.0±10.6%	5.1±10.6%
Proton Flux [cm ⁻² s ⁻¹] with E _{kin} > 10 MeV	12.7	7.5	4.9	5.0
Pion [±] Flux [cm ⁻² s ⁻¹]	37.46±5.7%	55.9±3.1%	47.5±2.4%	28.5±2.8%
Pion [±] Flux [cm ⁻² s ⁻¹] with E _{kin} > 10 MeV	37.2	55.8	47.5	1.3
Sum Flux with E _{kin} > 10 MeV	384	268	187	129

Table 3.4: Particle fluxes (particles/cm²/s) for minimum bias Pb-Pb running (**non-absorber side**)[2]

Layers	1	2	3	4
Neutron Flux [cm ⁻² s ⁻¹]	1625.6±1.3%	1638.4±2.1%	1625.6±1.2%	1626±1.3%
Neutron Flux [cm ⁻² s ⁻¹] with E _{kin} > 10 MeV	111.4	74.2	57.2	45.6
Proton Flux [cm ⁻² s ⁻¹]	19.5±9.6%	9.2±11.5%	8.1±19.3%	4.6±8.5%
Proton Flux [cm ⁻² s ⁻¹] with E _{kin} > 10 MeV	19.2	9.1	7.9	4.5
Pion [±] Flux [cm ⁻² s ⁻¹]	114.4±1.0%	65.7±2.5%	46.7±4.0%	31.0±3.0%
Pion [±] Flux [cm ⁻² s ⁻¹] with E _{kin} > 10 MeV	114.3	65.4	46.6	31.0
Sum Flux with E _{kin} > 10 MeV	245	149	112	81

Error estimates per run

- **SEUs in RCU main FPGA**

Table 8.1: Expected numbers of SEUs for the different scoring regions in the TPC detector

	<i>μ-absorber side</i>					
Sector	1	2	3	4	5	6
SEU/(FPGA s) [$\times 10^{-6}$]	2.4 ± 0.4	2.0 ± 0.4	1.6 ± 0.3	1.1 ± 0.2	0.9 ± 0.2	0.8 ± 0.1
	<i>non-absorber side</i>					
SEU/(FPGA s) [$\times 10^{-6}$]	1.6 ± 0.3	1.3 ± 0.2	0.9 ± 0.2	0.7 ± 0.1	0.6 ± 0.1	0.5 ± 0.1

- **Errors per run (4 hours)**

	Errors per run (4 hours) per TPC system
RCU	3.7
SIU	1.0
DCS	1.9

Conclusion (1)

- SRAM based FPGAs
 - Error rate is so low that one can cope with it – if SEUs can be detected instantaneously
 - ALTERA FPGAs do not provide real-time readback of configuration data nor disclose format of bitstream
 - Better choice: XILINX Virtex-II Pro FPGAs
 - » Real-time (= while running) readback of configuration data for verification
 - » Partial reconfiguration while running
 - » Existing infrastructure, running under linux (e.g. on DCS board), allowing full and high level control of the FPGA internals while running

Conclusion (2)

- Alternative: FLASH based FPGA (Actel)
 - ProASIC^{Plus} FLASH Family FPGAs
 - Preliminary irradiation results
 - » Device: APA075
 - » Test method: reading back configuration
 - » Failure (probably latch-up) after a fluence of 3.7×10^{11} protons/cm² \cong dose (E_{dep} of 30 MeV protons in 300 μm Si) of 500 Gy (check!)
 - » Expected fluence in 10 years of ALICE: $\sim 10^{11}$ protons/cm² (5.7 Gy)
 - » Further tests necessary

Table 8: Particle fluences and total absorbed doses per 10 ALICE years.

Scoring region of TPC electronics	Absorber side	Non-absorber side
Neutron Fluence [cm ⁻²]	$(0.6-1.1) \times 10^{11}$	0.4×10^{11}
Neutron Fluence [cm ⁻²] with $E_{\text{kin}} > 10$ MeV	$(2.4-8.4) \times 10^9$	$(1.1-2.8) \times 10^9$
Proton Fluence [cm ⁻²] with $E_{\text{kin}} > 10$ MeV	$(1.2-3.2) \times 10^8$	$(1.1-4.8) \times 10^8$
Pion Fluence [cm ⁻²] with $E_{\text{kin}} > 10$ MeV	$(0.7-1.4) \times 10^9$	$(0.8-2.9) \times 10^9$
Kaon Fluence [cm ⁻²] with $E_{\text{kin}} > 10$ MeV	$(2.4-7.6) \times 10^7$	$(3.3-19.3) \times 10^7$
Total Dose [Gy]	$(0.8-2.5) \times 10^0$	$(0.3-5.7) \times 10^0$

Next steps – a proposal

- **Develop SEU detection strategies**
- **Decide to migrate RCU-FPGA to XILINX**
- **Select appropriate device w.r.t. resources (e.g. number of I/O cells)**
- **Decide to keep DCS board unchanged**
- **Keep Actel-FPGA as fallback solution**
- **Port RCU design to new develop environment**
- **Port existing reconfiguration scheme to DCS board**
- **Verify expected performance under irradiation**
 - XILINX test @ OCL in June
 - System test @ TSL in fall with large beam spot (\varnothing 30cm)
- **Update RCU-layout**